

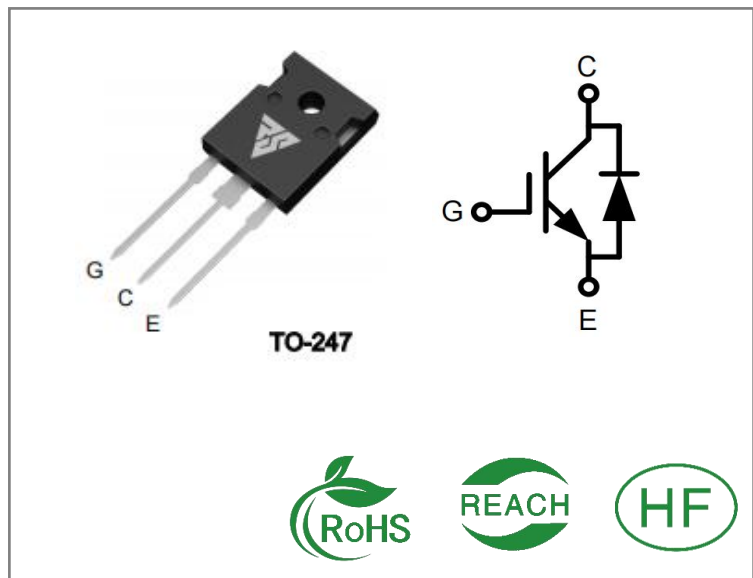
IF	V <sub>ce(sat)</sub>	VCES
40A	1.91V	1200V

**Applications:**

- EV Charging
- Uninterruptible Power Supply (UPS)
- Inverters

**Features:**

- 1200V trench gate/field termination process
- Very low V<sub>ce(sat)</sub>
- Low switching loss
- Positive temperature coefficient in V<sub>ce(sat)</sub>


**Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RSG40N120HW	T0-247-3	RSG40N120HW	Tube	30 PCS

**Absolute Maximum Ratings** T<sub>c</sub>= 25°C unless otherwise specified

Symbol	Parameter	RSG40N120HW	Units
VCES	Collector-Emitter Voltage	1200	V
VGES	Gate- Emitter Voltage	±20	V
IC	Continuous DC collector current TC = 100 °C	40	A
IC <sub>rm</sub>	Repetitive peak collector current tp=1 ms	80	A
P <sub>tot</sub>	Total Power Dissipation @ TC = 25°C	270	W
T <sub>stg</sub>	Storage Temperature	- 40to150	°C
TL	Maximum Temperature for Soldering	260	°C

**Thermal Characteristic**

Symbol	Parameter	RSG40N120HW	Units
R <sub>thJC</sub>	Thermal Resistance, Junction to case for IGBT	0.38	K/ W

**Electrical Characteristics** ( $T_C=25^{\circ}\text{C}$  unless otherwise noted)

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions	
Static Characteristics							
V(BR)CES	Collector-Emitter Breakdown Voltage	1200	-	--	V	V <sub>GE</sub> =0V,I <sub>CE</sub> =1mA	
ICES	Collector-Emitter Leakage Current	-	-	1	mA	V <sub>GE</sub> =0V, V <sub>CE</sub> =1200V	
IGES	Gate to Emitter Leakage current	-	-	200	nA	V <sub>GE</sub> =+20V, V <sub>CE</sub> =0V	
VCE(sat)	Collector-Emitter Saturation Voltage	-	1.91	2.3	V	I <sub>C</sub> =40A V <sub>GE</sub> =15	T <sub>j</sub> =25° C
	Gate Threshold Voltage	-	2.36	--	V	V	T <sub>j</sub> =175° C
VGE(th)	Collector-Emitter Breakdown Voltage	4.5	5.1	5.7	V	I <sub>C</sub> =1.5mA,V <sub>CE</sub> =V <sub>GE</sub>	
Gfs	Transconductance		27		S	I <sub>C</sub> =15A,V <sub>CE</sub> =20V	
Dynamic Characteristics							
Cies	Input Capacitance	-	2510	--	PF	V <sub>CE</sub> =25V, V <sub>GE</sub> =0V, f=100KHz	
Coes	Output Capacitance	-	210	--			
Cres	Reverse Transfer Capacitance	-	106	--			
Qg	Total Gate Charge		212		uC	V <sub>GE</sub> =15V 、 I <sub>C</sub> =40A V <sub>CE</sub> =960V	
Switching Characteristics							
td(ON)	Turn-on Delay Time	-	17	--	ns	V <sub>CE</sub> =600V, I <sub>C</sub> =40A, V <sub>GE</sub> =+/-15V,  R <sub>g</sub> =12Ω, Inductive Load	
t <sub>r</sub>	Rise Time	-	70				
td(OFF)	Turn-Off Delay Time	-	150	--			
t <sub>f</sub>	Fall Time	-	85	--			
E <sub>on</sub>	Turn-On Switching Loss	-	3.45	--	mJ		
E <sub>off</sub>	Turn-Off Switching Loss	-	5.72				

**Diode Maximum Ratings** ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions
VRRM	Repetitive Peak Reverse Voltage	1200	V	$T_C = 25^\circ\text{C}$
IF	Forward Current	40	A	$T_C = 100^\circ\text{C}$
IFRM	Repetitive Peak Forward Surge Current	80	A	$t_p = 1\text{ ms}$

**Characteristics Values** ( $T_C = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Min.	Typ.	Max.	Test Conditions	Unit
VF	Forward Voltage		2.0 1.74	2.5	IF = 40A, $V_{GE} = 0\text{V}$ $T_J = 25^\circ\text{C}$ IF = 40A, $V_{GE} = 0\text{V}$ $T_J = 175^\circ\text{C}$	V
IRM	Peak reverse recovery current		13 27		VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 25^\circ\text{C}$ VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 175^\circ\text{C}$	A
Qrr	Reverse Recovery Charge		2.55 7.62		VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 25^\circ\text{C}$ VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 175^\circ\text{C}$	uC
trr	Reverse Recovery time		450 700		VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 25^\circ\text{C}$ VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 175^\circ\text{C}$	ns
Erec	Reverse recovered energy		1.04 3.08		VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 25^\circ\text{C}$ VR = 600V, IF = 40A, $V_{GE} = -15\text{V}$ diF/dt = 400A/us $T_J = 175^\circ\text{C}$	mJ
RthJC	Diode Thermal Resistance, Junction		0.45			K/ W
Tvj op	Temperature under switching conditions	-40		175		$^\circ\text{C}$

Typical Feature Curve

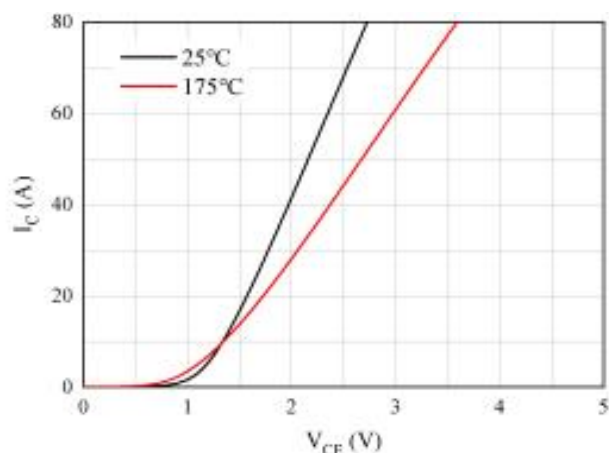


图 1. 典型输出特性 ( $V_{GE}=15V$ )

Figure 1. Typical output characteristics ( $V_{GE}=15V$ )

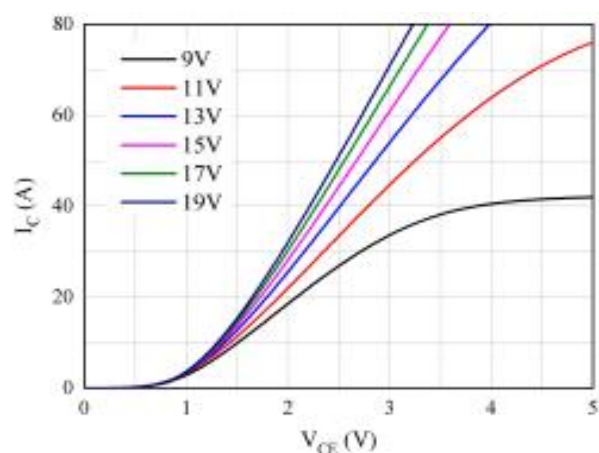


图 2. 典型输出特性 ( $T_{vj}=175^{\circ}C$ )

Figure 2. Typical output characteristics ( $T_{vj}=175^{\circ}C$ )

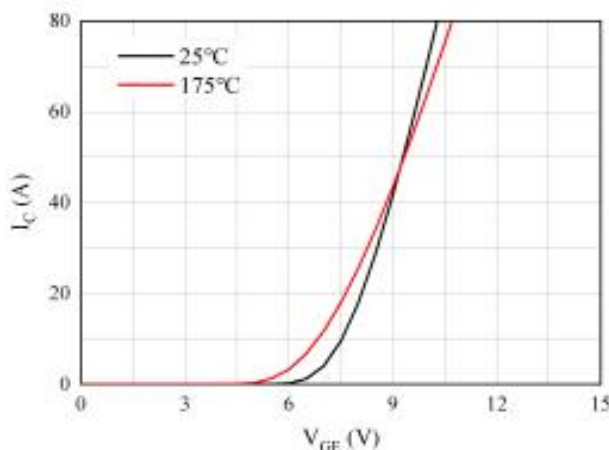


图 3. 典型传输特性 ( $V_{CE}=20V$ )

Figure 3. Typical transfer characteristic ( $V_{CE}=20V$ )

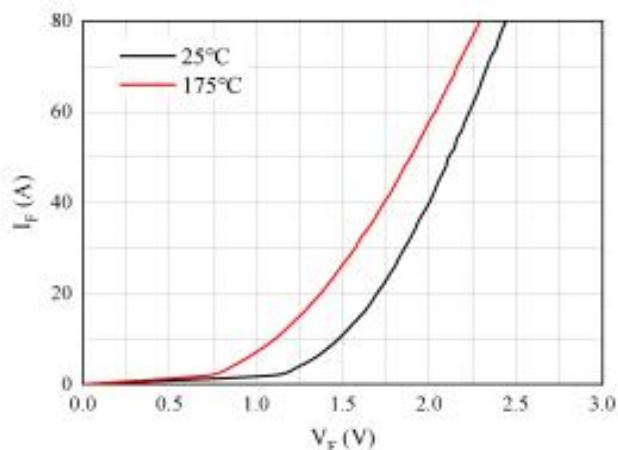


图 4. 正向偏压特性 二极管

Figure 4. Forward characteristic of Diode

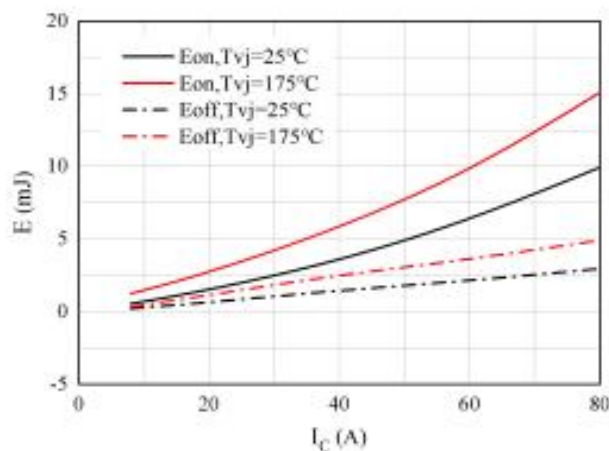


图 5. 开关损耗

Figure 5. Switching losses of IGBT  
 $V_{GE}=\pm 15V$ ,  $R_{Gon}=12\Omega$ ,  $R_{Goff}=12\Omega$ ,  $V_{CE}=600V$

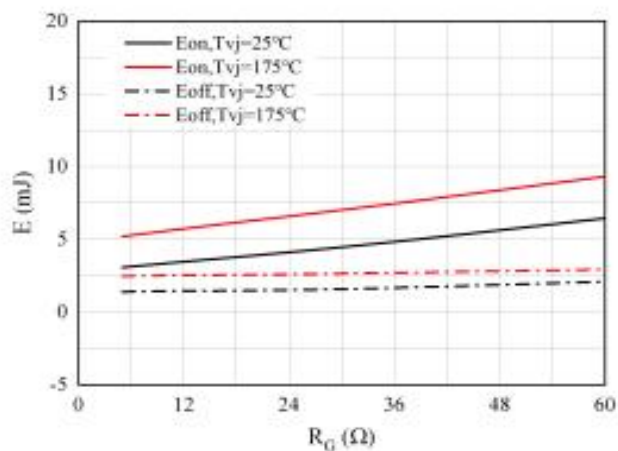


图 6. 开关损耗

Figure 6. Switching losses of IGBT  
 $V_{GE}=\pm 15V$ ,  $I_C=40A$ ,  $V_{CE}=600V$

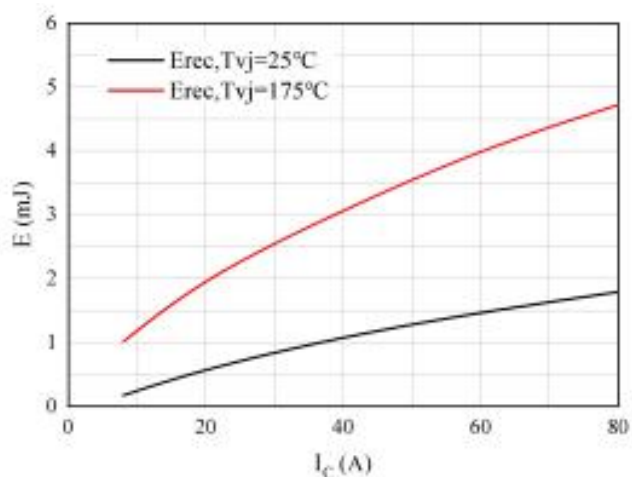


图 7. 开关损耗 二极管  
Figure 7. Switching losses of Diode  
 $R_{gon}=12\Omega$ ,  $V_{CE}=600V$

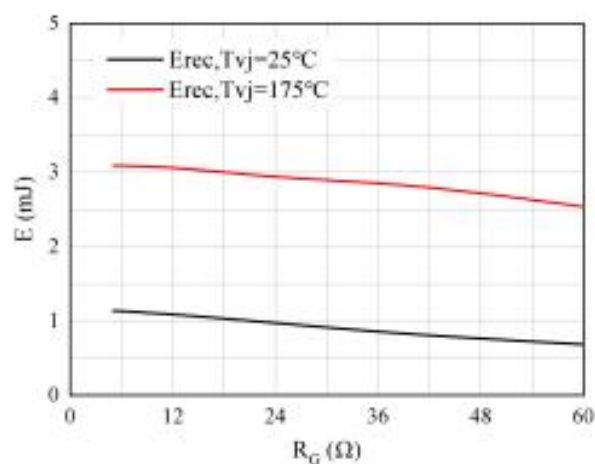


图 8. 开关损耗 二极管  
Figure 8. Switching losses of Diode  
 $I_F=40A$ ,  $V_{CE}=600V$

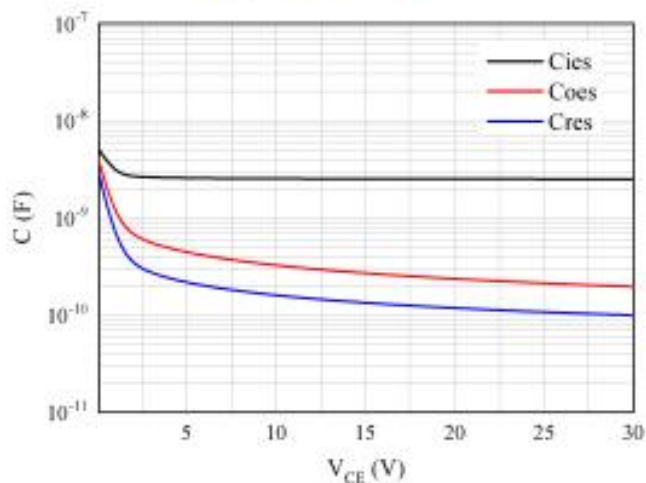
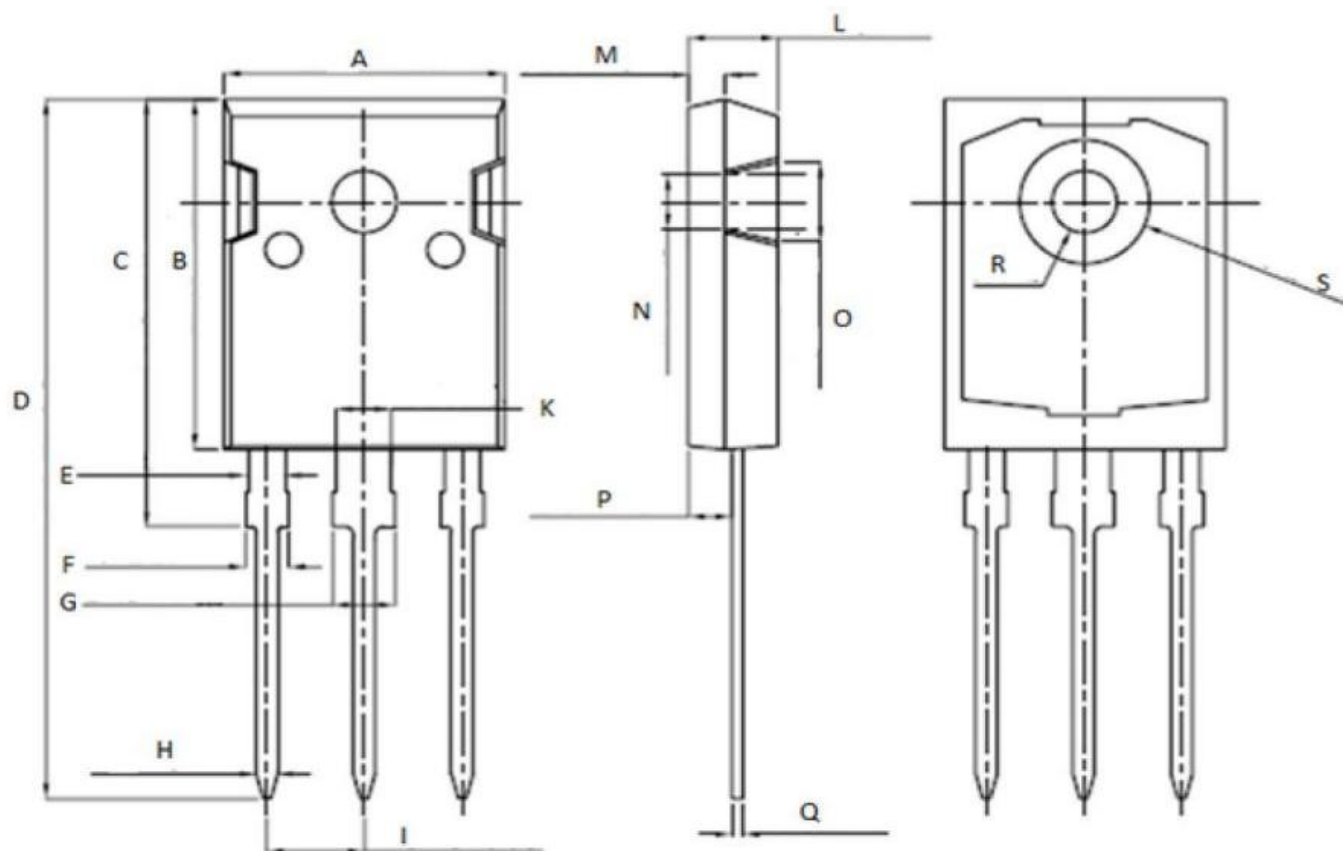


图 9. 电容特性  
Figure 9. Capacitance characteristic

Package outline drawing(TO-247-3 Unit: mm )



Unit: mm		
Symbol	Min.	Max.
A	15.95	16.25
B	20.85	21.25
C	20.95	21.35
D	40.5	40.9
E	1.9	2.1
F	2.1	2.25
G	3.1	3.25
H	1.1	1.3
I	5.40	5.50

Unit: mm		
Symbol	Min.	Max.
K	2.90	3.10
L	4.90	5.30
M	1.90	2.10
N	4.50	4.70
O	5.40	5.60
P	2.29	2.49
Q	0.51	0.71
R	φ 3.5	φ 3.7
S	φ 7.1	φ 7.3



**Disclaimers:**

Reasunos Semiconductor Technology CO.,LTD(Reasunos)reserves the right to make changes without notice in order to improve reliability,function or design and to discontinue any product or service without notice .Customers should obtain the latest relevant information before orders and should verify that such information in current and complete.All products are sold subject to Reasunos's terms and conditions supplied at the time of orderacknowledgement.

Reasunos Semiconductor Technology CO.,LTD warrants performance of its hardware products to the specifications at the time of sale.Testing,reliability and quality control are used to the extene Reasunos deems necessary to support this warrantee. Except where agreed upon by contractual agreement,testing of all parameters of each product is not necessarily performed. Reasunos Semiconductor Technology CO.,LTD does not assume any liability arising from the use of any product or circuit designs described herein.Customers are responsible for their products and applications using Reasunos's components.To minimize risk,customers must provide adequate design and operating safeguards.

Reasunos Semiconductor Technology CO.,LTD does not warrant or convey any license either expressed or implied under its patent rights,nor the rights of others.Reproduction of information in Reasunos's data sheets or data books is permissible only if reproduction is without modification or alteration.Reproduction of this information with any alteration is an unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such altered documentation.

Resale of Reasunos's products with statements different from or beyond the parameters stated by Reasunos Semiconductor Technology CO.,LTD for that product or service voids all express or implied warranties for the associated Reasunos's product or service and is unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such statements.

**Life Support Policy:**

Reasunos Semiconductor Technology CO.,LTD's Products are not authorized for use as critical components in life support devices or systems without the expressed written approval of Reasunos Semiconductor Technology CO.,LTD.

As used herein:

1. Life support devices or systems are devices or systems which: a.are intended for surgical implant into the human body, b.support or sustain life, c.whose failure to when properly used in accordance with instructions for used provided in the labeling,can be reasonably expected to result in significant injury to the user.

2.A critical component is any component of a life support device or system whose failure to system whose failure to perform can be reasonably expected to cause the failure of the life support device or system,or to affect its safety or effectiveness.